



## Description

The FQD2N60CTF uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge. This device is suitable for use as a Battery protection or in other Switching application.

## General Features

$V_{DS} = 600V$   $I_D = 2A$

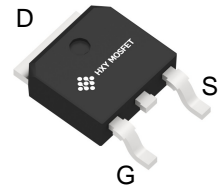
$R_{DS(ON)} < 4.5\Omega$  @  $V_{GS}=10V$

## Application

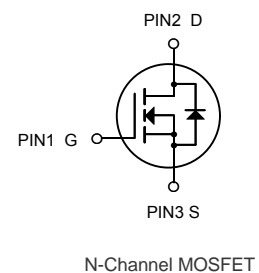
Battery protection

Load switch

Uninterruptible power supply



TO-252-2L  
(TO-252(DPAK))



N-Channel MOSFET

## Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)
FQD2N60CTF	TO-252-2L(TO-252(DPAK))	HXY MOSFET	2500

## Absolute Maximum Ratings $T_c=25^\circ C$ unless otherwise noted

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	600	V
$V_{GS}$	Gate-Source Voltage	$\pm 30$	V
$I_D@T_c=25^\circ C$	Continuous Drain Current, $V_{GS}$ @ 10V <sup>[1]</sup>	2	A
$I_D@T_c=100^\circ C$	Continuous Drain Current, $V_{GS}$ @ 10V <sup>[1]</sup>	1.2	A
$I_{DM}$	Pulsed Drain Current <sup>[2]</sup>	8	A
$P_D@T_c=25^\circ C$	Total Power Dissipation <sup>[1]</sup>	31	W
$T_{STG}$	Storage Temperature Range	-55 to 150	$^\circ C$
$T_J$	Operating Junction Temperature Range	-55 to 150	$^\circ C$
$R_{\theta JA}$	Thermal Resistance Junction-ambient <sup>[6]</sup>	100	$^\circ C/W$
$R_{\theta JC}$	Thermal Resistance Junction-Case <sup>[1]</sup>	4.0	$^\circ C/W$



### Electrical Characteristics (T<sub>J</sub>=25°C, unless otherwise noted)

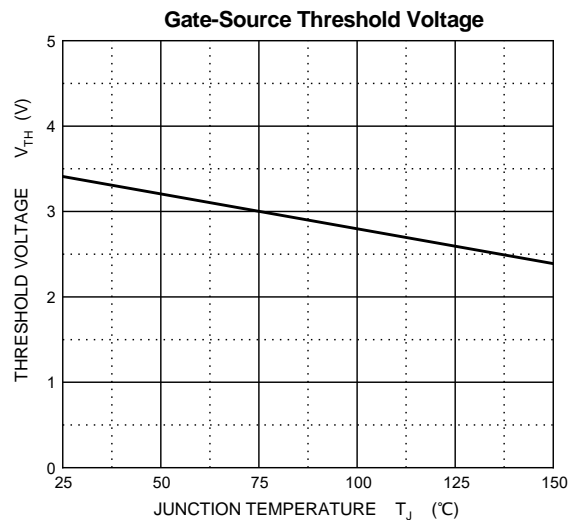
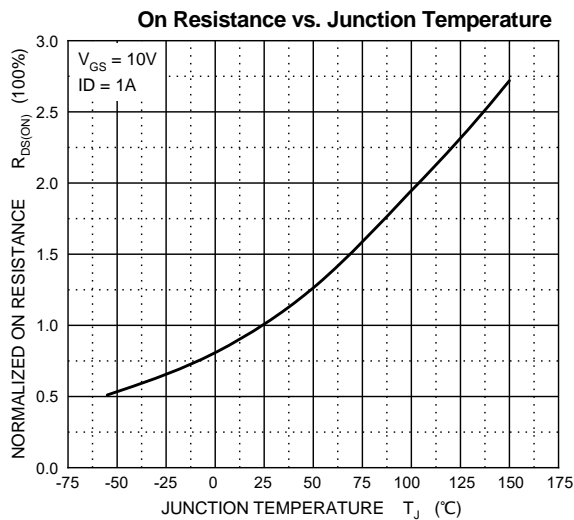
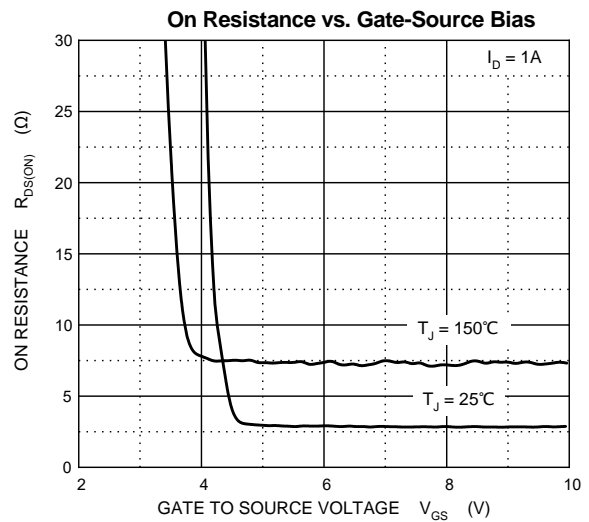
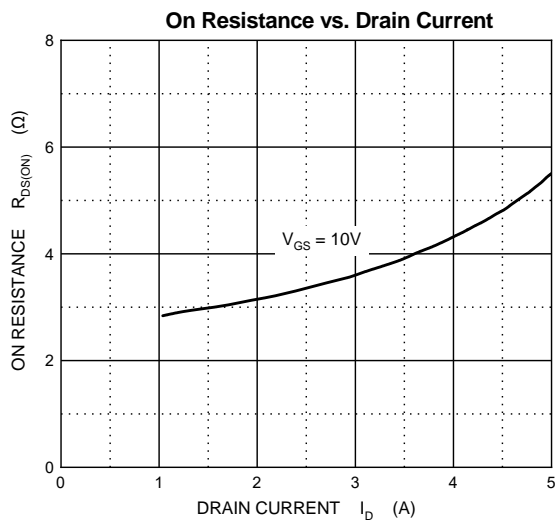
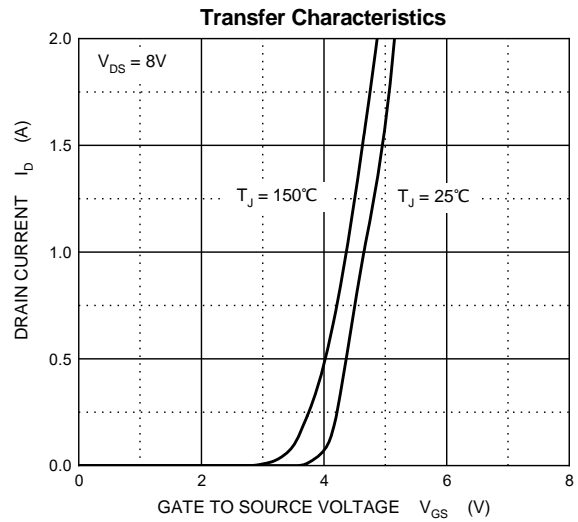
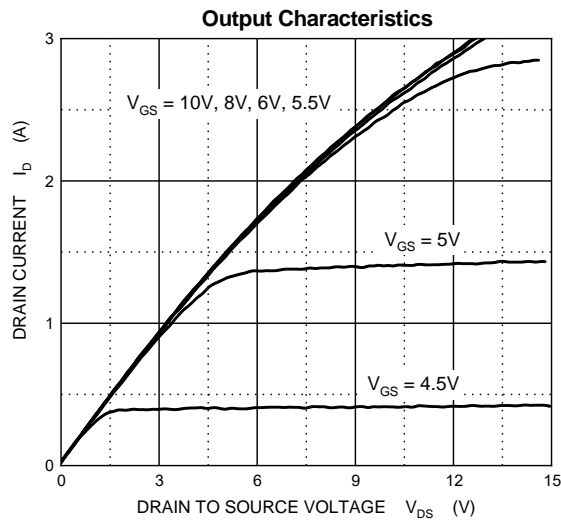
Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Off characteristics						
Drain-source breakdown voltage	V <sub>(BR) DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	600			V
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> =600V, V <sub>GS</sub> =0V			1.0	μA
Gate-body leakage current	I <sub>GSS</sub>	V <sub>DS</sub> =0V, V <sub>GS</sub> =±30V			±100	nA
On characteristics <sup>[4]</sup>						
Gate-threshold voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	2.0	3.4	4.0	V
Static drain-source on-sate resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =1A		3.7	4.5	Ω
Dynamic characteristics <sup>[5]</sup>						
Input capacitance	C <sub>iss</sub>	V <sub>DS</sub> =25V,V <sub>GS</sub> =0V, f =1MHz		322		pF
Output capacitance	C <sub>oss</sub>			38		
Reverse transfer capacitance	C <sub>rss</sub>			7		
Gate resistance	R <sub>g</sub>	f =1MHz		5.7		Ω
Switching characteristics <sup>[5]</sup>						
Total gate charge	Q <sub>g</sub>	V <sub>GS</sub> =10V, V <sub>DS</sub> =25V, I <sub>D</sub> =2A		1.6		nC
Gate-source charge	Q <sub>gs</sub>			2.1		
Gate-drain charge	Q <sub>gd</sub>			6.2		
Turn-on delay time	t <sub>d(on)</sub>	V <sub>DD</sub> =25V, V <sub>GS</sub> =10V, R <sub>G</sub> =18Ω, I <sub>D</sub> =2A		1.8		nS
Turn-on rise time	t <sub>r</sub>			3.2		
Turn-off delay time	t <sub>d(off)</sub>			7.4		
Turn-off fall time	t <sub>f</sub>			7.6		
Drain-Source Diode Characteristics						
Drain-source diode forward voltage <sup>[4]</sup>	V <sub>SD</sub>	V <sub>GS</sub> =0V, I <sub>S</sub> =2A			1.4	V
Continuous drain-source diode forward current <sup>[1]</sup>	I <sub>S</sub>				2.0	A
Pulsed drain-source diode forward current <sup>[2]</sup>	I <sub>SM</sub>				8.0	A
Reverse recovery time	t <sub>rr</sub>	dIF/dt = 100A/μs, I <sub>S</sub> = 2A, V <sub>DD</sub> = 400V		192		ns
Reverse recovery charge	Q <sub>rr</sub>			1027		nC

Notes:

- 1.T<sub>C</sub>=25°C Limited only by maximum temperature allowed.
- 2.P<sub>W</sub>≤10μs, Duty cycle≤1%.
- 3.EAS condition: V<sub>DD</sub>=150V, V<sub>GS</sub>=10V, L=10mH, R<sub>G</sub>=25Ω Starting T<sub>J</sub> = 25°C.
- 4.Pulse Test : Pulse Width≤300μs, duty cycle ≤2%.
- 5.Guaranteed by design, not subject to production.
- 6.The value of RθJA is measured with the device in a still air environment with T<sub>A</sub>=25°C.

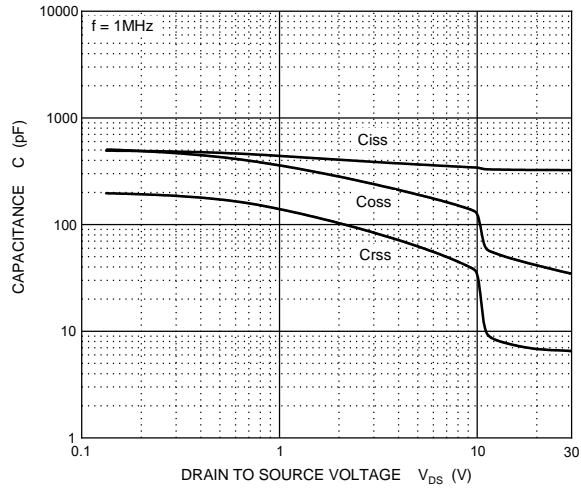


## Typical Characteristics

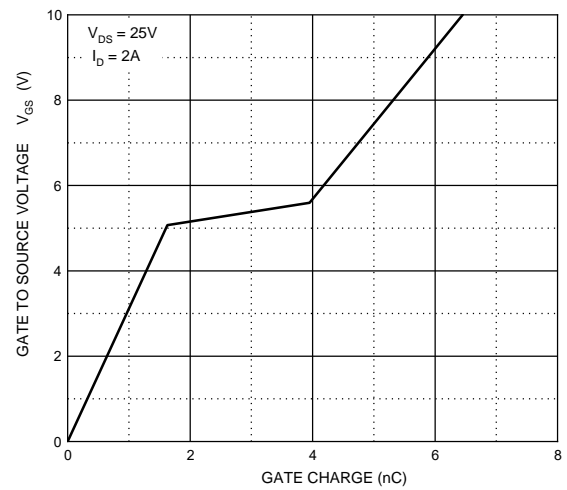




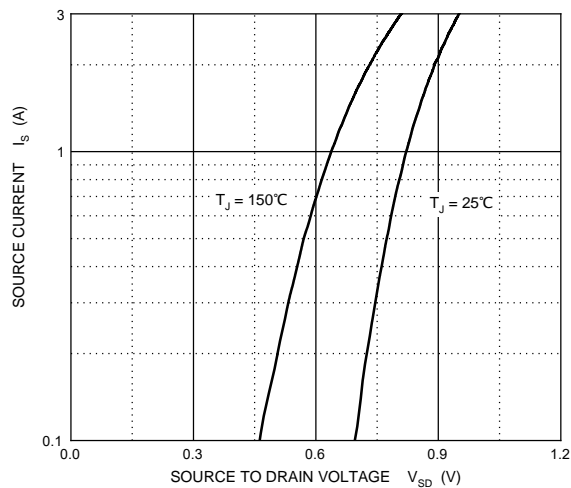
Typical Capacitances



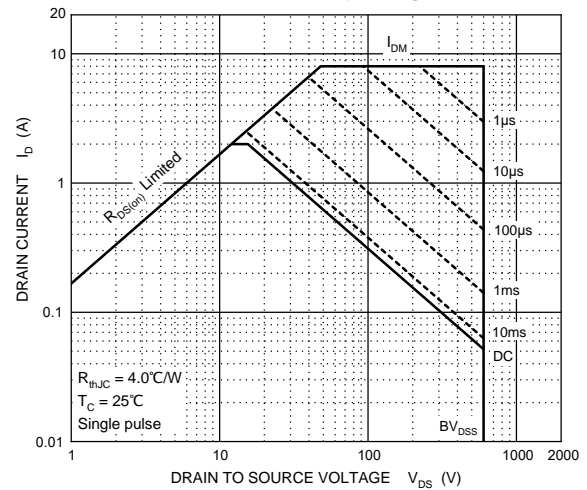
Gate Charge



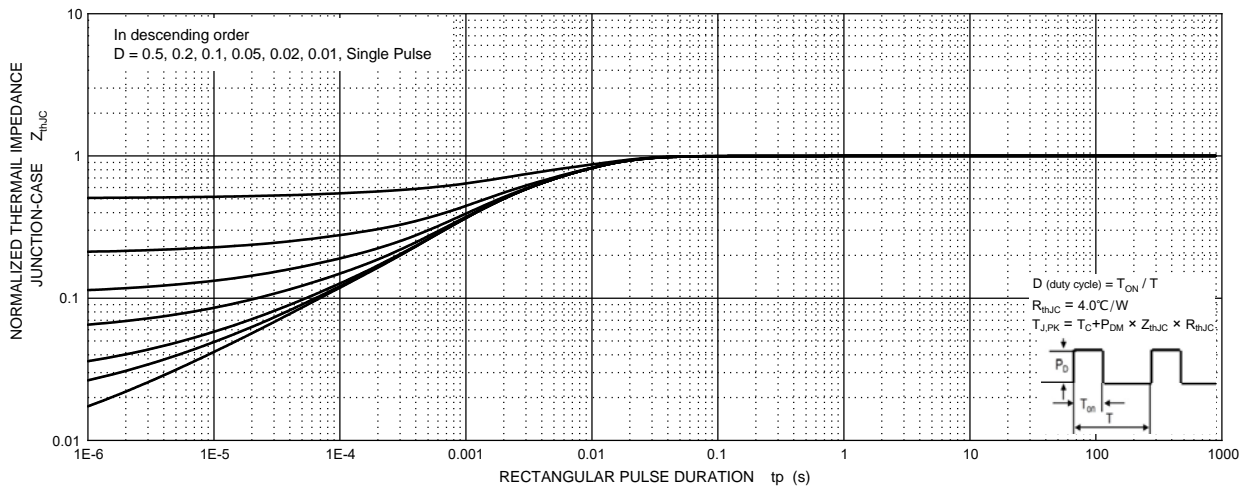
Source-Drain Diode Forward Characteristics



Maximum Safe Operating Area



Transient Thermal Impedance, Junction-Case

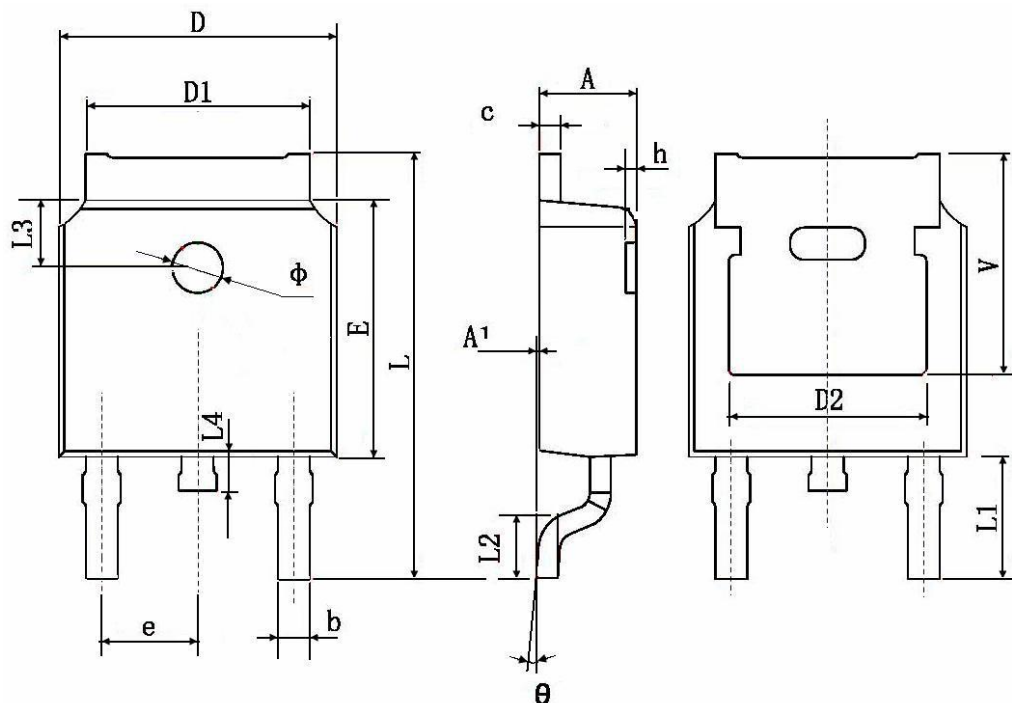




FQD2N60CTF

## N-Channel Enhancement Mode MOSFET

## TO-252-2L(TO-252(DPAK)) Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.660	0.860	0.026	0.034
c	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	0.483 TYP.		0.190 TYP.	
E	6.000	6.200	0.236	0.244
e	2.186	2.386	0.086	0.094
L	9.800	10.400	0.386	0.409
L1	2.900 TYP.		0.114 TYP.	
L2	1.400	1.700	0.055	0.067
L3	1.600 TYP.		0.063 TYP.	
L4	0.600	1.000	0.024	0.039
Φ	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.350 TYP.		0.211 TYP.	



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